

60V N-Channel Enhancement Mode MOSFET

Description

The XPX200N06RD uses advanced technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 60V$ $I_D = 200A$

$R_{DS(ON)} < 1.6m\Omega$ @ $V_{GS}=10V$

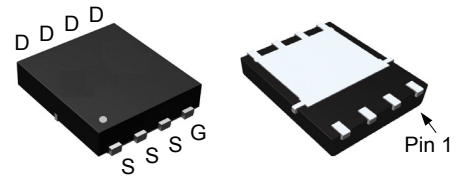
Application

Battery protection

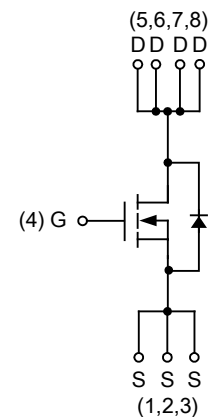
Load switch

Uninterruptible power supply

Pin Description



DFN5x6A-8_EP



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
XPX200N06RD	DFN5*6-8L	XPX200N06RD XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DS}	Drain source voltage	60	V
V_{GS}	Gate source voltage	± 20	V
$I_D @ T_A=25^\circ C$	Continuous drain current	200	A
$I_D @ T_A=70^\circ C$	Continuous drain current	110	A
IDM	Pulsed drain current	700	A
$P_D @ T_A=25^\circ C$	Power dissipation	114	W
EAS	Single pulsed avalanche energy	353	mJ
TSTG	Storage Temperature Range	-55 to 150	$^\circ C$
T_j	Operation and storage temperature	-55 to 150	$^\circ C$
$R_{\theta JC}$	Thermal resistance, junction-case	1.1	$^\circ C/W$
$R_{\theta JA}$	Thermal resistance, junction-ambient ⁵⁾	25	$^\circ C/W$

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit	
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	60	71	-	V	
IGSS	Gate-body Leakage Current	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA	
IDSS T _J =25°C	Zero Gate Voltage Drain Current	V _{DS} = 60V, V _{GS} = 0V	-	-	1	μA	
IDSS T _J =100°C			-	-	100		
VGS(th)	Gate-Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	2.8	4.0	V	
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} = 10V, I _D = 20A	-	1.6	2.2	mΩ	
gfs	Forward Transconductance ⁴	V _{DS} = 10V, I _D = 20A	-	89	-	S	
Ciss	Input Capacitance	V _{DS} = 30V, V _{GS} = 0V, f = 1MHz	-	4150	-	pF	
Coss	Output Capacitance		-	1075	-		
Crss	Reverse Transfer Capacitance		-	33	-		
RG	Gate Resistance	f = 1MHz	-	2.2	-	Ω	
Qg	Total Gate Charge	V _{GS} = 10V, V _{DS} = 30V, I _D = 20A	-	69	-	nC	
Qgs	Gate-Source Charge		-	17.2	-		
Qgd	Gate-Drain Charge		-	21	-		
td(on)	Turn-on Delay Time	V _{GS} = 10V, V _{DD} = 30V, = 3Ω, I _D = 20A	-	17.5	-	ns	
t _r	Rise Time		R _G	-	18.1		-
td(off)	Turn-off Delay Time		-	-	42		-
t _f	Fall Time		-	-	22		-
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/μs	-	57	-	ns	
Qrr	Body Diode Reverse Recovery Charge		-	67.9	-	nC	
VSD	Diode Forward Voltage ⁴	I _S = 20A, V _{GS} = 0V	-	-	1.2	V	
IS	Continuous Source Current T _C = 25°C		-	-	180	A	

Note

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=38A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

Typical Characteristics

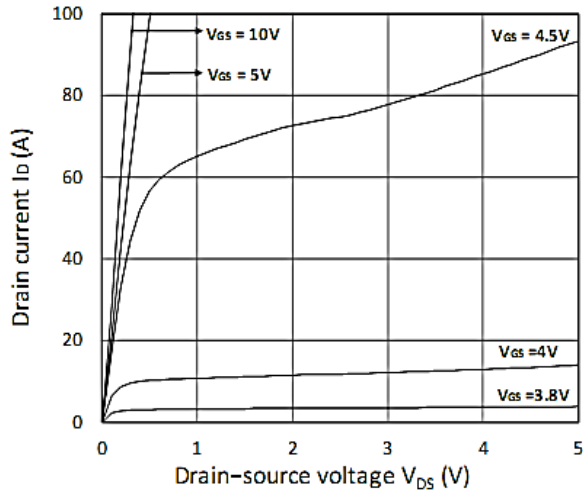


Figure 1. Output Characteristics

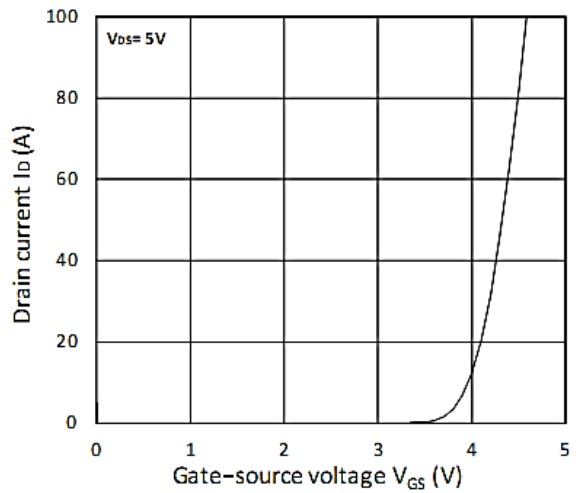


Figure 2. Transfer Characteristics

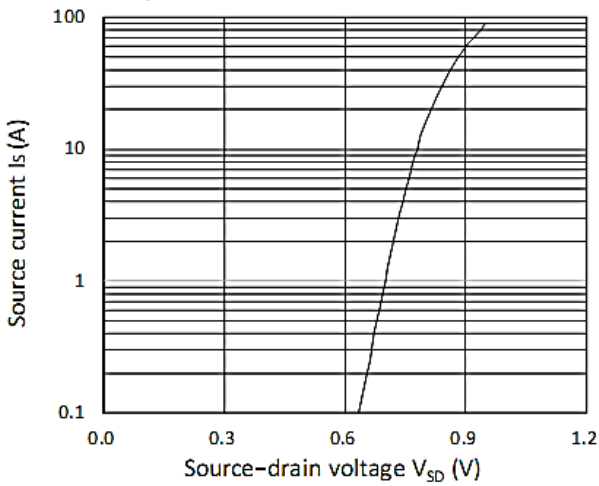


Figure 3. Forward Characteristics of Reverse

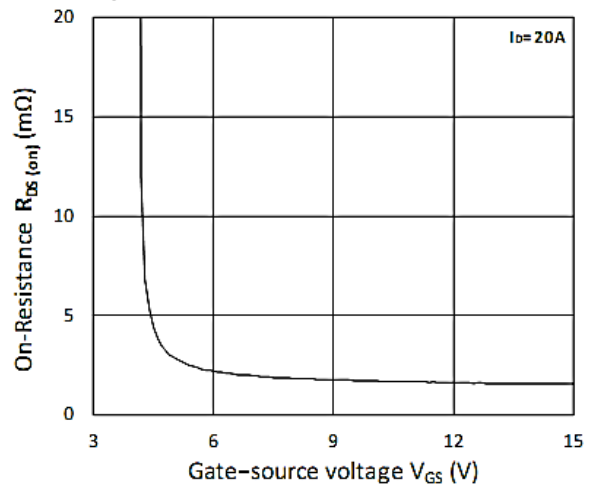


Figure 4. $R_{DS(ON)}$ vs. V_{GS}

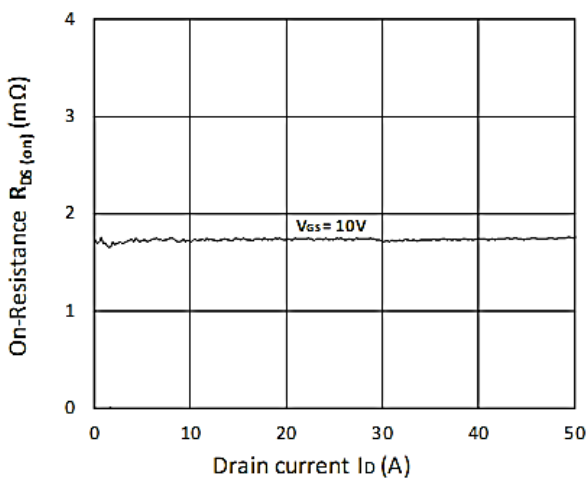


Figure 5. $R_{DS(ON)}$ vs. I_D

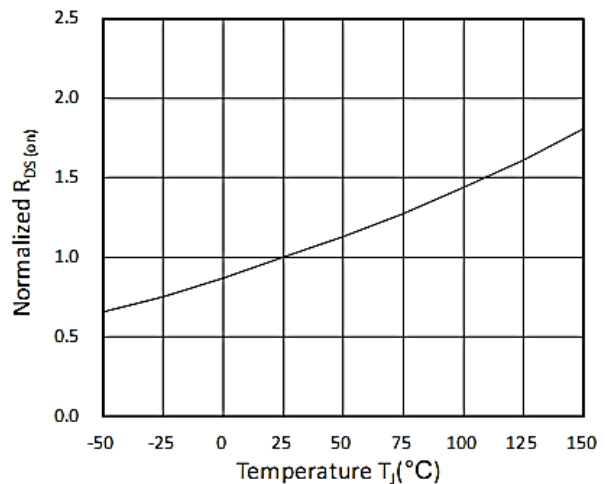


Figure 6. Normalized $R_{DS(on)}$ vs. Temperature

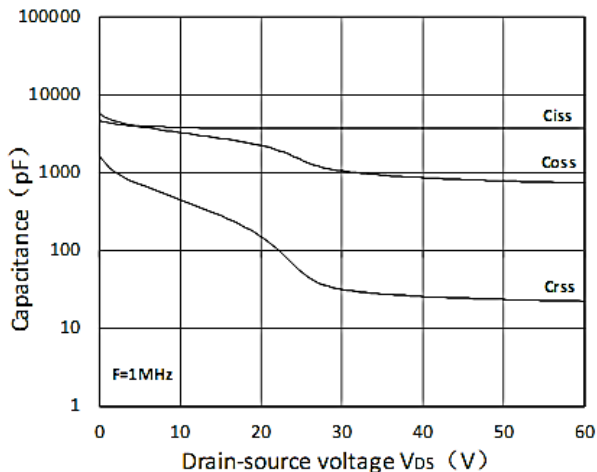


Figure 7. Capacitance Characteristics

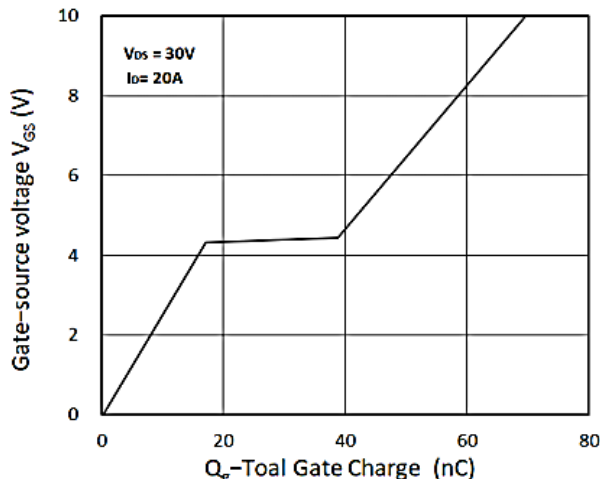


Figure 8. Gate Charge Characteristics

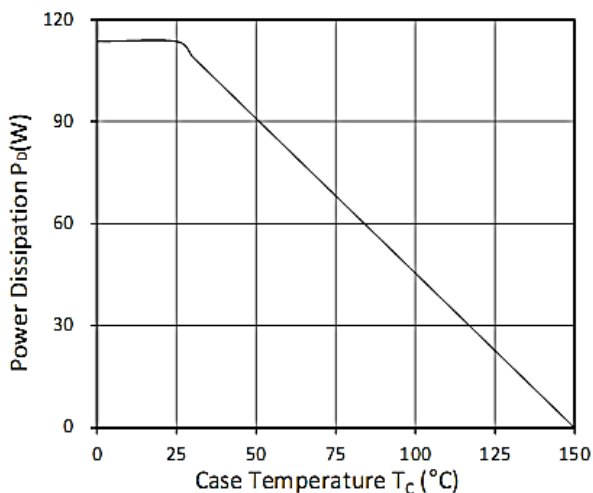


Figure 9. Power Dissipation

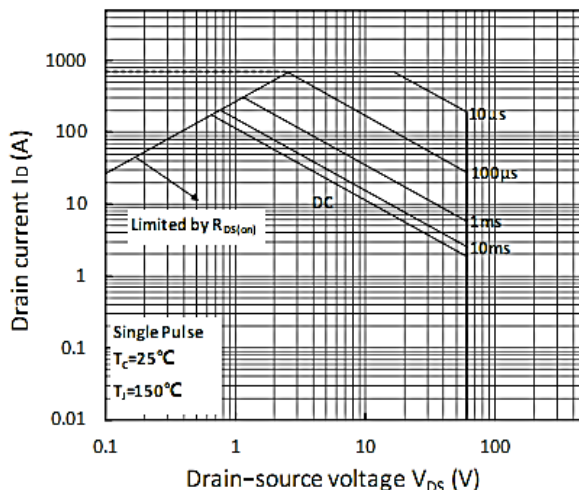


Figure 10. Safe Operating Area

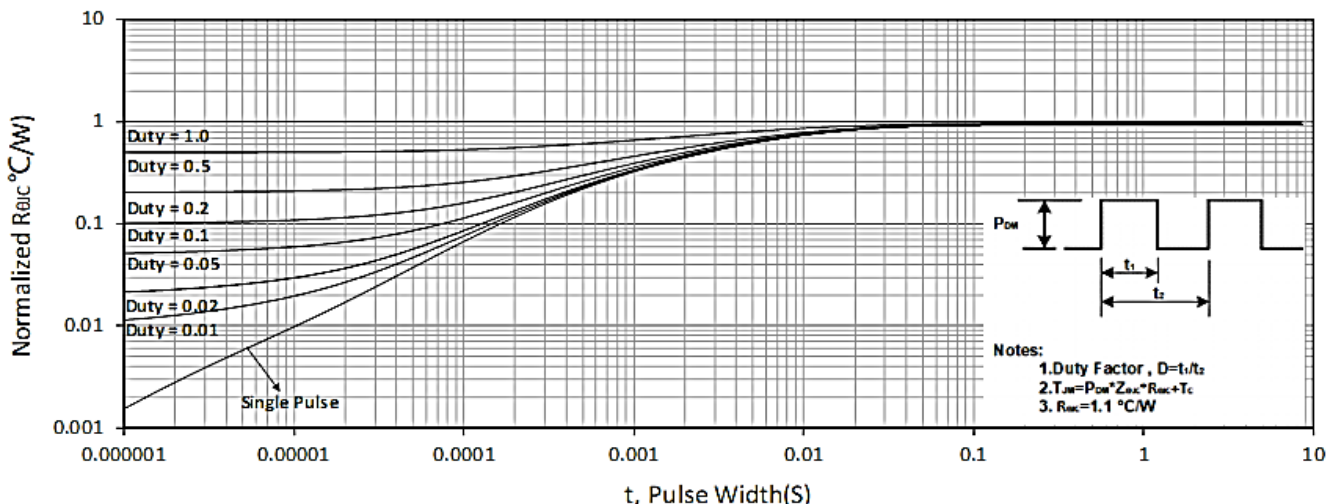
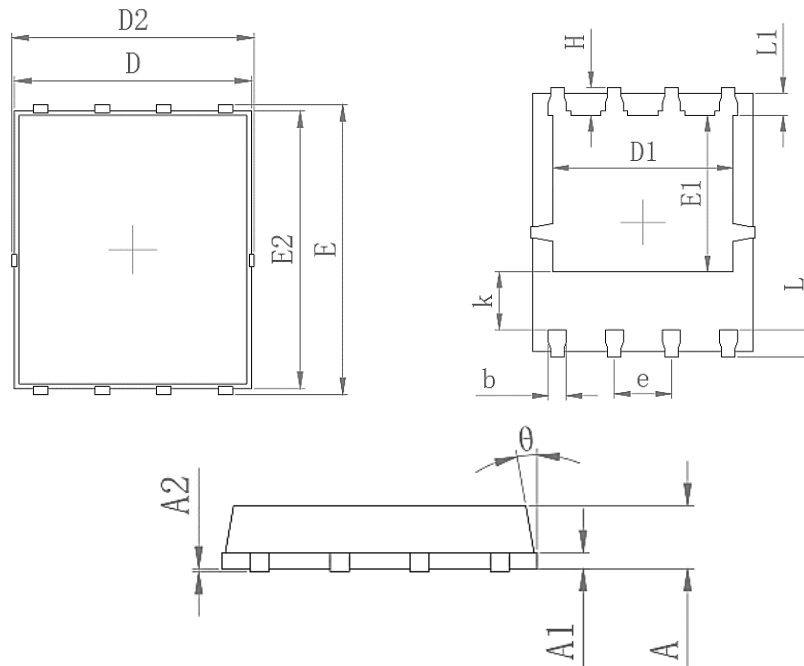


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN5X6-8L-XZT Single


Symbol	Common	
	mm	
	Mim	Max
A	0.90	1.10
A1	0.254 REF	
A2	0-0.05	
D	4.824	4.976
D1	3.910	4.110
D2	4.944	5.076
E	5.924	6.076
E1	3.375	3.575
E2	5.674	5.826
b	0.350	0.450
e	1.270	
L	0.534	0.686
L1	0.424	0.576
K	1.190	1.390
H	0.549	0.701
Φ	8°	12°

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec ±1sec
Pb-Free device	260°C +0/-5°C	5sec ±1sec



This integrated circuit can be damaged by ESD. UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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